

Certificate of Analysis

ULTRAgrade[™] Solution Indium ICP / ICP-MS Standard 1000 µg/mL

Catalog Number: ICP-049 Lot Number: R00677 Job Number: J00016582 Lot Issue Date: 07/11/2013 Expiration Date: 08/31/2020

Starting Material: Indium metal

Starting Material Purity: 99.999%, 99.999% Starting Material Lot #: BH02305, BH02449

Matrix: 1% nitric acid in low TOC water (< 50 ppb)

Atomic Weight In: 114.82

Certified Value: 1000 ± 2 µg/mL

This Certified Reference Material (CRM) was manufactured and verified in accordance with ULTRA's ISO 9001 registered quality system. The analyte concentration(s) were prepared and verified by an ISO Guide 34 / ISO 17025 accredited laboratory, and compared to calibration standards independently prepared using NIST SRM(s). The certified value and uncertainty value at the 95% confidence level for each analyte is determined gravimetrically.

Classical Wet Assay Method: Theoretical, based on gravimetric measurements

Confirmation by Inductively Coupled Plasma Spectroscopy (ICP / ICP/MS) vs. NIST SRM 3124a

ULTRA uses purified acids, 18 megohm double deionized water, calibrated Class A glassware & meticulously cleaned bottles in the manufacturing of ULTRAgrade standards. Balances used in the manufacturing of this standard are calibrated with weights traceable to NIST in compliance with ANSI/NCSL Z-540-1 and ISO 9001.

Trace Metallic Impurities in Solution Standard in µg/mL:

*	ΑI	< 0.005	ND	*	Ga	< 0.005	ND	*	Nb	< 0.005	ND	<u>n</u>	S		
*	Sb	< 0.005	ND	*	Ge	< 0.005	ND	*	Os	< 0.005	ND	*	Ta	< 0.005	ND
*	As	< 0.005	ND	*	Au	< 0.005	ND	*	Pd	< 0.005	ND	*	Te	< 0.005	ND
*	Ba	< 0.005	ND	*	Hf	< 0.005	ND	*	Р	< 0.005	ND	*	Tb	< 0.005	ND
*	Be	< 0.005	ND	*	Но	< 0.005	ND	*	Pt	< 0.005	ND	*	ΤI	< 0.005	ND
*	Bi	< 0.005	ND	S	In			*	K	< 0.005	ND	*	Th	< 0.005	ND
*	В	< 0.005	ND	*	lr	< 0.005	ND	*	Pr	< 0.005	ND	*	Tm	< 0.005	ND
*	Cd	<1	D	*	Fe	< 0.005	ND	*	Re	< 0.005	ND	*	Sn	< 0.005	ND
*	Ca	< 0.005	ND	*	La	< 0.005	ND	*	Rh	< 0.005	ND	*	Ti	< 0.005	ND
*	Ce	< 0.005	ND	*	Pb	< 0.005	ND	*	Rb	< 0.005	ND	*	W	< 0.005	ND
*	Cs	< 0.005	ND	*	Li	< 0.005	ND	*	Ru	< 0.005	ND	*	U	< 0.005	ND
*	Cr	< 0.005	ND	*	Lu	< 0.005	ND	*	Sm	< 0.005	ND	*	V	< 0.005	ND
*	Co	< 0.005	ND	*	Mg	< 0.005	ND	*	Sc	< 0.005	ND	*	Yb	< 0.005	ND
*	Cu	< 0.005	ND	*	Mn	< 0.005	ND	*	Se	< 0.005	ND	*	Υ	< 0.005	ND
*	Dy	< 0.005	ND	n	Hg			*	Si	< 0.005	ND	*	Zn	< 0.005	ND
*	Εr	< 0.005	ND	*	Mo	< 0.005	ND	*	Ag	< 0.005	ND	*	Zr	< 0.005	ND
*	Eu	< 0.005	ND	*	Nd	< 0.005	ND	*	Na	< 0.005	ND				
*	Gd	< 0.005	ND	*	Ni	< 0.005	ND	*	Sr	< 0.005	ND				

* - element checked for I – spectral interference ND – not detected D – detected

rference n – not checked for s – solution standard element

Density of Solution (measured at 20.00°C ± 0.05°C): 1.0074 g/mL

ACCREDITED A

ISO 17025:2005 Accredited A2LA Cert. No. 0851.01 ISO 9001:2000 Registered TUV USA, Inc. Cert. No. 06-1004 William J. Lear Quality Assurance Manager